



11-18-.04

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By: *[Handwritten signature]*
LINDA E. HASTINGS

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No. 50-1290.

Attorney Docket No.: NEKO 19.481 (100806-00091)

IN THE UNITED STATES PATENT AND TRADEMARK
OFFICE

Inventor: Kazunori KISHIMOTO
Serial No.: 10/083,447
Filed: February 26, 2002
Title: **METHOD OF TESTING A SEMICONDUCTOR
INTEGRATED CIRCUIT AND METHOD AND
APPARATUS FOR GENERATING TEST PATTERNS**
Examiner: John P. Trimmings
Group Art Unit: 2133

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

S I R :

In response to the Office Action mailed on August 17,
2004, the period for responding thereto having been set to
expire after November 17, 2004, please amend the subject
application as follows: